H7 L C &\$% @GE % 3.3V CMOS DIL14 TCXO

Features and Benefits

High frequency stability(up to ±0.5 ppm over -40°C to +85°C) Low power consumption (up to 15 mA) DIL14 package design 3.3V CMOS output

Typical Applications

Microwave Communication Mobile Devices

Description

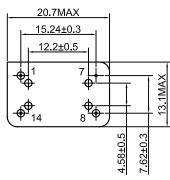
TCXO2013LSQ1 offers high frequency stability and low power consumption in DIL14 package with wide range of stability vs. operating temperature options to suit the different applications needs.

Mechanical Drawing & Pin Connections

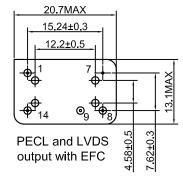
Drawing No:

MD1400**-(

Bottom View



Side View XMM8.0 Side View NIMS8.0 NIMS8.0 NIMS8.0 NIMS8.0 NIMS8.0



Pin Connections: (Without EFC)

PIN#	Symbol	CONNECTION					
1	N.C or Comp OUT	No Connection or Complementary RF Output (PECL and LVDS)					
7	GND	Ground					
8	RF OUT	RF Output					
9	Pi	Pin Not Present					
14	Vs	Supply Voltage					

Pin Connections: (With EFC)

PIN#	Symbol	CONNECTION		
1	Vc	Control Voltage(EFC)		
7	GND	Ground		
8	RF OUT	RF Output		
9	Comp OUT	Complementary RF Output (PECL and LVDS)		
14	Vs	Supply Voltage		

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Unit in mm 1mm = 0.0394 inches



Dynamic Engineers Inc.

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Specifications

Oscillator	Com	Condition		Value		Unit	Note
Specification	Sym	Condition	Min.	Тур.	Max.	Ullit	Note
Frequency Range			1		200	MHz	
Signal Waveform				HCMOS			
Output Load				15		pF	
Amplitude			According t	o relevant Lo	ogic Standard		
Power Supply							
Supply Voltage	Vs		3.15	3.30	3.45	V	
Current Consumption (Note 2)				15 ~ 50		mA	
Frequency Adjustment Range							
Mechanical (internal trimmer)			±3			ppm	Ordering Option = blank
Electronic Frequency Control (EFC)			±5			ppm	Ordering Option = "V"
EFC Voltage	Vc		0.15	1.65	3.15	V	
EFC Slope	$\Delta f / \Delta V_C$		Positive				
EFC Input Impedance			100			kΩ	
Frequency Stability							
Vs Operating Temperature			±0.5		±5.0	ppm	Refer to ordering options
Vs Supply Voltage changes	Vs	±5%		±0.1	±0.3	ppm	
Vs Load changes		±10%			±0.2	ppm	
Long Term Aging Per Year		@ +40°C			±1.0	ppm	
Environmental Conditions							
Operating Temperature Range			-40		+85	°C	Refer to ordering options
Storage Temperature Range			-55		+105	°C	
Enclosure (see drawing) L x W x H		max	2	20.7 x 13.1 x	7.5	mm	IEC 60679-3 CO21
Weight					5	g	

Notes:

- 1. Terminology and test conditions are according to IEC60679-1 and MIL-PRF-55310, unless otherwise stated
- 2. Depending on frequency and supply voltage
- 3. Reduced package heig H = 5.1mm max. on request
- 4. All combinations of options might not be available. Please consult DEI for details

Absolute Maximum Ratings

Parameter	Sym	Min	Max.	Unit	Condition
Supply Voltage	V_S	-0.5	V _s +10%	V	V _s to GND
Control Voltage	V _C	-0.5	6	V	V _c to GND

Handling and Testing

Parameter	Procedure	Condition	
Electrostatic Discharge (ESD)			
THD devices	IEC60749-26	HBM	2000V
SMD devices	IEC60749-27	MM	200V
Washable	Yes		
RoHS Compliant	Yes	•	



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Ordering Options

Frequency Stability			erature wer)	Temperature (Upper)		
Code	Stability [ppm]	Code	T (°C)	Code	T (°C)	
1	±0.5	1	0	1	+50	
2	±1.0	2	-10	2	+60	
3	±1.5	3	-20	3	+70	
4	±2.0	4	-30	4	+75	
5	±2.5	5	-40	5	+80	
6	±3.0			6	+85	
7	±3.5					
8	±5.0					

Ordering Codes

	Model	EFC	Frequency in MHz (up to 4 digits)	Frequency Stability	Minimum Operating Temperature	Maximum Operating Temperature
ĺ	TCXO2013LSQ1	_ or "V"	xxx.yyyy	t	W	Z

Example: TCXO2013LSQ1-20.0000-5-5-6 has the following specifications

EFC= no EFC controlFrequency= 20.0000 MHzStability= $\pm 2.5 \text{ ppm}$ Operating Temperature= $-40^{\circ}\text{C to } +85^{\circ}\text{C}$

Environmental Conditions

Test	IEC 60068 Part	IEC 60679-1 Clause	MIL-STD- 202G Method	MIL-STD- 810F Method	MIL-PRF- 55310D Clause	Test Conditions (IEC)
Sealing tests	2-17	5.6.2	112E		3.6.1.2	Gross leak: Test Qc,
(if applicable)						Fine leak: Test Qk
Solderability	2-20	5.6.3	208H		3.6.52	Test Ta Method 1
Resistance to	2-58		210F		3.6.48	Test Td₁ Method 2
soldering heat						Test Td ₂ Method 2
Shock	2-27	5.6.8	213B	516.4	3.6.40	Test Ea, 3 x per axes 100g,
						6 ms half-sine pulse
Vibration	2-6	5.6.7.1	201A	516.4-4	3.6.38.1	Test Fc, 30 min per axes,
sinusoidal			204D		3.6.38.2	10 Hz – 55 Hz 0,75mm; 55 Hz – 2 kHz, 10g
Vibration,	2-64	5.6.7.3	214A	514.5	3.6.38.3	Test Fdb
random					3.6.38.4	
Endurance tests			108A			
- aging		5.7.1			4.8.35	30 days @+85°C
 extended aging 		5.7.2				1000h, 2000h, 8000h @ +85°C